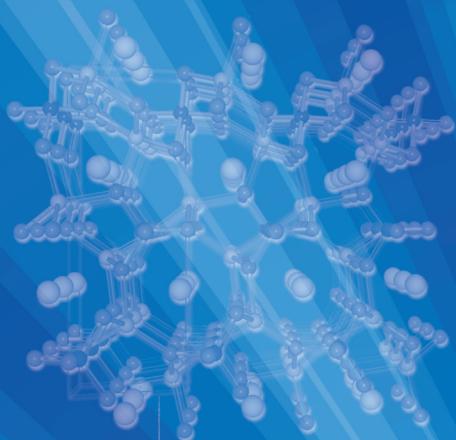


# Powder Diffraction PDJ

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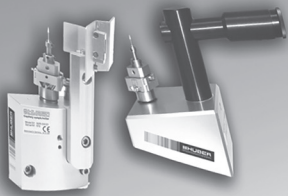
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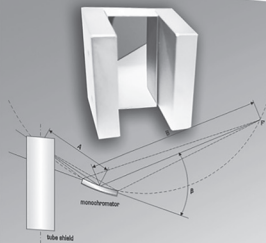


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## EDITORIAL

- Michela Brunelli,  
Paolo Scardi and  
Angela Altomare
- Proceedings of the 15th European Powder Diffraction Conference
- S1

## TECHNICAL ARTICLE

- Jacek Podwórny,  
Alicja Pawełek and  
Jerzy Czechowski
- Crystal structure of  $\text{Al}_5\text{O}_3\text{N}_3$  (15R)
- S2
- M. Abdellatif, L. Rebuffi,  
H. Khosroabadi, M. Najdawi,  
T. Abu-Hanieh, M. Attal and  
G. Paolucci
- The SESAME materials science beamline for XRD applications
- S6
- P. Mikula, M. Vrána,  
J. Šaroun and V. Em
- Neutron diffraction studies of a double-crystal (+n,-m) setting containing a fully asymmetric diffraction geometry (FAD) of a bent perfect crystal (BPC)
- S13
- Kunihisa Sugimoto,  
Shogo Kawaguchi and  
Michitaka Takemoto
- Structural characterization of caffeine–oxalic acid co-crystals from the powder diffraction pattern at the SPring-8 BL02B2 beamline
- S19
- D. Ectors, F. Goetz-  
Neunhoeffler and J. Neubauer
- Routine (an)isotropic crystallite size analysis in the double-Voigt approximation done right?
- S27
- Andreas Leineweber
- Reflection splitting-induced microstrain broadening
- S35
- Abderrahim Aatiq,  
Asmaa Marchoud,  
Hajar Bellefqih and  
My Rachid Tigha
- Structural and Raman spectroscopic studies of the two  $M_{0.50}\text{SbFe}(\text{PO}_4)_3$  ( $M = \text{Mg}, \text{Ni}$ ) NASICON phases
- S40
- E. A. Efimova,  
V. V. Sikolenko,  
D. V. Karpinsky,  
I. O. Troyanchuk, S. Pascarelli,  
C. Ritter, M. Feygenson,  
S. I. Tiutiunnikov and V. Efimov
- A combined diffraction and EXAFS study of  $\text{LaCoO}_3$  and  $\text{La}_{0.5}\text{Sr}_{0.5}\text{Co}_{0.75}\text{Nb}_{0.25}\text{O}_3$  powders
- S52
- Alexander Missyul,  
Ivan Bolshakov and  
Roman Shpanchenko
- XRD study of phase transformations in lithiated graphite anodes by Rietveld method
- S56
- A. Serafini, L. Lutterotti,  
S. Gross and S. Gialanella
- Characterization of nanograined powder samples using the Rietveld method applied to electron diffraction ring patterns
- S63
- Jens-Erik Jørgensen,  
Yaroslav Filinchuk and  
Vladimir Dmitriev
- Tilting of semi-rigid  $\text{GaF}_6$  octahedra in  $\text{GaF}_3$  at high pressures
- S69
- Jessica Bauer,  
Robert Haberkorn and  
Guido Kickelbick
- Chemical redox reactions and extended PXRD-characterization of triphylite-type compounds  $AM_{0.5}\text{Fe}_{0.5}\text{PO}_4$  ( $A = \text{Li}, \text{Na}; M = \text{Mn}, \text{Co}$ )
- S74

K. Dudek, J. Podwórny, M. Dulski, A. Nowak and J. Peszke	X-ray investigations into silica/silver nanocomposite	S82
Pablo Pardo, Marek Andrzej Kojdecki, José Miguel Calatayud, José María Amigó and Javier Alarcón	Crystalline microstructure of boehmites studied by multi-peak analysis of powder X-ray diffraction patterns	S87
Tomasz Goryczka and Karolina Dudek	Structure of multi-functional calcium phosphates/TiO <sub>2</sub> layers deposited on NiTi shape-memory alloy	S99
Daria Petrova, Dina Deyneko, Sergey Stefanovich and Bogdan Lazoryak	Crystal structure refinement of new vanadates Ca <sub>8-x</sub> Pb <sub>x</sub> CdBi(VO <sub>4</sub> ) <sub>7</sub>	S106
A. N. Zaloga, I. S. Yakimov and P. S. Dubinin	Determination of the [Pt(NH <sub>3</sub> ) <sub>5</sub> Cl]Br <sub>3</sub> crystal structure from X-ray powder diffraction data using multi-population genetic algorithm	S110
R. Caliandro, B. D. Belviso, C. Cuocci, S. Fuertes, V. Sicilia, J. C. Hanson, G. Tutuncu, E. Doorhyee and A. Altomare	Dynamic characterization of structural changes in vapochromic compounds by pair distribution function	S118
Angela Altomare, Fulvio Ciriaco, Corrado Cuocci, Aurelia Falcicchio and Flavio Fanelli	Combined powder X-ray diffraction data and quantum-chemical calculations in EXPO2014	S123
Angela Altomare, Nicola Corriero, Corrado Cuocci, Aurelia Falcicchio, Anna Moliterni and Rosanna Rizzi	Main features of <i>QUALX2.0</i> software for qualitative phase analysis	S129
Elisa Cappelletto, Luca Rebuffi, Alberto Flor and Paolo Scardi	Microstructural effects of high-energy grinding on poorly soluble drugs: the case study of efavirenz	S135
Dieter Jehnichen, Doris Pospiech, Peter Friedel, Andriy Horechyy, Andreas Korwitz, Andreas Janke, Franziskus Näther, Christine M. Papadakis, Jan Perlich and Volker Neu	Effects of nanoparticles on phase morphology in thin films of phase-separated diblock copolymers	S141
V. Efimov, V. Sikolenko, I. O. Troyanchuk, D. Karpinsky, E. Efimova, S. I. Tiutiunnikov, B. N. Savenko, D. Novoselov and D. Prabhakaran	Anomalous behavior of displacement correlation function and strain in lanthanum cobalt oxide analyzed both from X-ray powder diffraction and EXAFS data	S151

Evgeny Yu. Filatov, Svetlana V. Cherepanova, Ilia V. Kochetygov, Yury V. Shubin and Sergey V. Korenev	Domain structure of CoIr nanoalloys	S155
Walid Oueslati, Nejmeddine Chorfi and Mohamed Abdelwahed	Effect of mechanical constraint on the hydration properties of Na-montmorillonite: study under extreme relative humidity conditions	S160
Dina V. Deyneko, Darya A. Petrova, Olga N. Leonidova, Ivan V. Nikiforov and Bogdan I. Lazoryak	Ferroelectric properties and structural refinement of whitlockite-type phosphate $\text{Ca}_{8.5}\text{Pb}_{0.5}\text{Ho}(\text{PO}_4)_7$	S168
Takashi Ida, Kento Wachi, Daiki Hattan, Shoki Ono, Shoji Tachiki, Yuki Nakanishi, Yasuhiro Sakuma, Akio Wada and Shin-ichi Towata	Analysis of powder diffraction data collected with synchrotron X-ray and multiple 2D X-ray detectors applying a beta-distribution peak profile model	S172
Ryoko Oishi-Tomiyasu	Application of convex optimization to identification of atomic species from diffraction patterns	S179
G. Dercz, I. Matuła, M. Zubko and J. Dercz	Phase composition and microstructure of new Ti–Ta–Nb–Zr biomedical alloys prepared by mechanical alloying method	S186
B. Peplinski, B. Adamczyk, P. Formanek, C. Meyer, O. Krüger, H. Scharf, S. Reinsch, M. Ostermann, M. Nofz, C. Jäger, C. Adam and F. Emmerling	Nanocrystalline and stacking-disordered $\beta$ -cristobalite $\text{AlPO}_4$ chemically stabilized at room temperature: synthesis, physical characterization, and X-ray powder diffraction data	S193
P. Rodrigues, F. M. Braz Fernandes, A. S. Paula, J. P. Oliveira, S. B. Ribeiro, E. N. Texeira and N. Schell	Microstructural characterization of NiTi shape memory alloy produced by rotary hot forging	S201
Claudia Aparicio, Jan Filip and Libor Machala	From Prussian blue to iron carbides: high-temperature XRD monitoring of thermal transformation under inert gases	S207
Marine Reynaud and Montse Casas-Cabanas	Order and disorder in NMC layered materials: a FAULTS simulation analysis	S213
Frantisek Lukac, Tomas Chraska, Orsolya Molnarova, Premysl Malek and Jakub Cinert	Effect of cryogenic milling on Al7075 prepared by spark plasma sintering method	S221
M. Bortolotti, L. Lutterotti and G. Peponi	Combining XRD and XRF analysis in one Rietveld-like fitting	S225

## CORRIGENDUM

E. A. Efimova,  
V. V. Sikolenko,  
D. V. Karpinsky,  
I. O. Troyanchuk,  
S. Pascarelli, C. Ritter,  
M. Feygenson,  
S. I. Tiutiunnikov and  
V. Efimov

A combined diffraction and EXAFS study of  $\text{LaCoO}_3$  and  $\text{La}_{0.5}\text{Sr}_{0.5}\text{Co}_{0.75}\text{Nb}_{0.25}\text{O}_3$   
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S231



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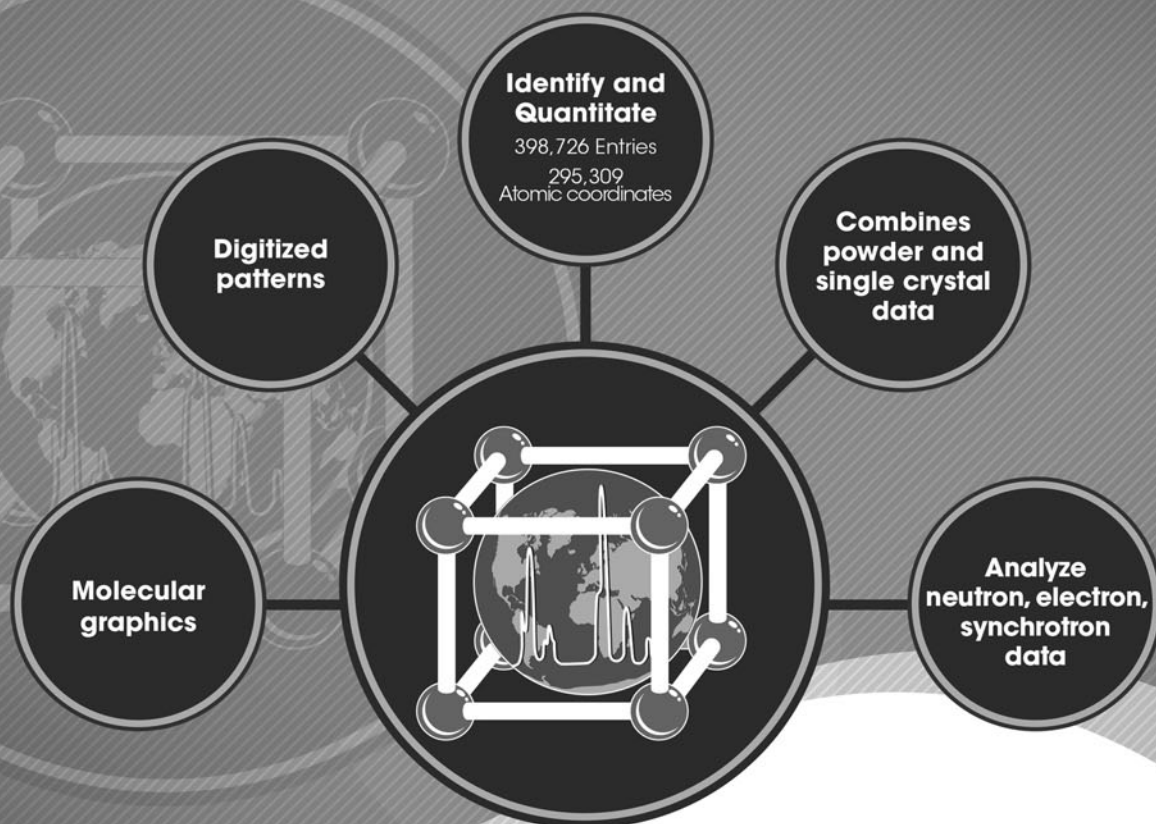
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